Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/670,792	NAGANO ET AL.
Examiner	Art Unit
Jim Vannucci	2828

SEARCHED				
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	1				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
olock, step, array, lens, 372/10, ofset, staggered	9/15/2005	٦V	